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PTO/SB/08a/b (08-03)
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Substitute for form 1449A/B/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	Not Yet Assigned
		Filing Date	Concurrently Herewith
		First Named Inventor	Peter Hoghoj
		Art Unit	WIA 2882
		Examiner Name	Not Yet Assigned J. Yun
Attorney Docket Number	XENOCs 3.3-002		
Sheet	1	of	1

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
J.Y.	AA	US-5,999,262-A	12-07-1999	Dobschal et al.	
J.Y.	AB	US-6,317,483-B1	11-13-2001	Chen	
J.Y.	AC	US-5,799,056-A	08-25-1998	Gutman	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
J.Y.	CA	SASANUMA, et al., "A point-focusing small angle x-ray scattering camera using a doubly curved monochromator of a W/Si multilayer.", Rev. Sci. Instrum., Vol. 37, No. 3, pp. 688-692, March 1, 1996.		

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Examiner Signature	Juric Yun	Date Considered	6-19-07
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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheets	1	of	1	Attorney Docket Number	XENOCs 3.3-002
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JY.	AA*	6,278,764	08-21-2001	Barbee, Jr. et al.	
JY.	AB*	5,619,548	04-08-1997	Koppel	

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Examiner Signature	<i>Jurie Yun</i>	Date Considered	6-19-07
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Used in Lieu of PTO/SB/08A/B
(Based on PTO 04-07 version)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete If Known	
				Application Number	10/518,284-Conf. #3519
				Filing Date	September 2, 2005
				First Named Inventor	Peter Hoghoj
				Art Unit	2882
				Examiner Name	C. C. G. Kao Yun
Sheet	1	of	2	Attorney Docket Number	XENOCs 3.3-002

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	AB*	US-6,317,483-B1	11-13-2001	Chen	
	AC*	US-5,799,056-A	08-25-1998	Gutman	
	AD*	US-6,276,764	08-21-2001	Barbee, Jr. et al.	
	AE*	US-5,619,548	04-08-1997	Koppel	
	AF*	US-6,041,099-A	03-21-2000	Gutman et al.	
	AG*	US-4,562,583-A	12-31-1985	Hoover et al.	
	AH*	US-5,127,028-A	06-30-1992	Wittry	
	AI*	US-20040096034-A1	05-20-2004	Michaelsen et al.	
	AJ*	US-5,142,561	08-25-1992	Doumas	
	AK*	US-6,285,506-B1	09-04-2001	Chen	
	AL*	US-6,226,349	05-01-2001	Schuster et al.	

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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	MM-DD-YYYY			
JY.	BA	EP-0115892	08-15-1984	Philips Nv		✓
JY.	BB	WO-02/103710-A2	12-27-2002	X-Ray Optical Systems, Inc.		✓
JY.	BC	GB-2217036-A	10-18-1989	Rosser		✓
JY.	BD	WO-108162	02-01-2001	Univ California		✓

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	CA	NAUDON et al., "New Apparatus for Grazing Reflectometry in the Angle-Resolved Dispersive Mode", J. Appl. Cryst, Vol. 22, Part 5, pp. 460-464, October 1, 1989.	
	CB	M.P. Ulmer, Production and performance of multilayer coated conic sections, Jul 2001, SPIE, Vol. 4496, page 127-133.	
	CC	M.P. Ulmer, The Fabrication of Wolter I multilayer coated optics via electroforming: an update, Jul 1999, SPIE, Vol. 3773, page 113-121.	
	CD	M. Schuster et al., Laterally Graded Multilayer Optics for X-ray Analysis, SPIE, Vol. 3767, Jul 1999, Page 183-198.	
	CE	Romaine et al., Multilayer Optics for Hard X-ray Astronomy, SPIE, Vol. 4138, Nov. 2000, page 120-125.	
	CF	HEADRICK et al., "Multilayer Optics for a Wiggler Beamline (invited), March 2002, Review of Scientific Instruments, Vol. 43, No. 3, p. 1476-1479.	
	CG	G.E. ICE, "Microbeam Forming Methods for Synchrotron Radiation," © 1997	

Examiner Signature	<i>Juric Yun</i>	Date Considered	6-19-07
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J.Y.	CH	OVONYX; Design News; "Focusing ring: first step toward scanning X-ray microscope," 13 pages	
J.Y.	CI	Research & Development, November 1988 by B. Volbert "New X-ray Spectrometer Technology Improves Both Speed and Accuracy," 8 pages	
J.Y.	CJ	MORAWE CH ET AL., entitled "Production of x-ray multilayer coatings by plasma sputtering" (VIDE; VIDE: SCIENCE, TECHNIQUE ET APPLICATIONS 1999 SOC FRANCAISE DU VIDE, FRANCE, vol. 4 (4), no. 294, 1999, pages 467-472)	
J.Y.	CK	PING LEE, entitled: "Uniform and graded multilayers as X-ray optical elements" (APPLIED OPTICS USA, vol. 22, no. 8, 15 April 1983 (1983-04-15), pages 1241-1246)	
J.Y.	CL	KLEINEBERG et al., "Bufferlayer and Caplayer Engineering of Mo/Si EUVL Multilayer Mirrors", Soft X-Ray and EUV Imaging Systems II, Daniel A. Tichenor, James A. Folta, Editors, Proceedings of SPIE, Vol. 4506 (2001), pp. 113-120.	
J.Y.	CM	NIGGEMEIER et al., "X-ray Reflectometer for the Diagnostics of Thin Films During Growth", Journal of Applied Crystallography (1997), 30, 905-908.	

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